Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
08/973,424	IEHISA ET AL.
Examiner	Art Unit
Phillip Nguyen	2828

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
DATE	EXMR			
6/25/2005	PN			
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